

<b>Notice of References Cited</b>	Application/Control No. 10/050,123	Applicant(s)/Patent Under Reexamination YEN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,995,017 A	11-1999	Marsh et al.	340/10.2
	B	US-6,275,682 B1	08-2001	Yen et al.	455/41.2
	C	US-2001/0056501 A1	12-2001	Law et al.	709/248
	D	US-2003/0014574 A1	01-2003	Kuo et al.	710/62
	E	US-2003/0014575 A1	01-2003	Wang et al.	710/62
	F	US-6,509,845 B1	01-2003	Tanaka, Hiroshi	341/22
	G	US-6,519,290 B1	02-2003	Green, Gary	375/259
	H	US-2003/0084210 A1	05-2003	Wu et al.	710/9
	I	US-2003/0083056 A1	05-2003	Wu et al.	455/420
	J	US-6,950,890 B2	09-2005	Liu et al.	710/72
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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